

WHAT IS CLAIMED IS:

1. A repair fuse box of a semiconductor device comprising:

a plurality of fuse boxes arranged in a longitudinal direction, each fuse box comprising a plurality of fuses arranged in a transverse direction;

5        signal connecting fuses arranged in each side portion of outermost fuses of the fuses which are selected from the fuses arranged in one or more fuse boxes of the plurality of fuse boxes to construct a unit fuse set and of which one side ends are connected mutually, the signal connecting fuses being connected to the outermost fuses; and

10        metal lines for connecting the signal connecting fuses to the fuses selected to construct a unit fuse box in an upper or lower fuse box.

2. The repair fuse box of a semiconductor device according to claim 1, wherein the signal connecting fuse is not cut under repair.

15        3. The repair fuse box of a semiconductor device according to claim 1, wherein a connection point of the signal connecting fuses and the outermost fuses is connected to an output terminal of an enable transistor in a repair address generating circuit.

20        4. The repair fuse box of a semiconductor device according to claim 1, wherein the signal connecting fuses and the fuses in the upper or lower fuse box are connected mutually through a contact process.